

# AN13080

## PCAL6524 debounce function implementation

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Application note

### Document information

Information	Content
Keywords	I <sup>2</sup> C-bus, SMBus, PCAL6524, Agile I/O, 24-bit generator purpose I/O expansion, switch debounce, bit-wise I/O programming, POR .
Abstract	This document describes the PCAL6524 debounce function implementation which includes debounce circuitry operation mechanism, registers settings as well as power consumption explanations.



## Revision history

Rev	Date	Description
v.1.0	20211213	Initial version

## 1 Introduction

The PCAL6524 is a 24-bit general purpose I/O expander that provides remote I/O expansion for most microcontroller families via the Fast-mode Plus (Fm+) I<sup>2</sup>C-bus interface. The ultra low-voltage interface allows for direct connection to a microcontroller operating down to 0.8 V.

The PCAL6524 fully meets the Fm+ I<sup>2</sup>C-bus specification at speeds to 1 MHz and implements Agile I/O, which are additional features specifically designed to enhance the I/O. These additional features are: programmable output drive strength, latchable inputs, programmable pull-up/pull-down resistors, maskable interrupt, interrupt status register, programmable open-drain or push-pull outputs.

Additional Agile I/O Plus features include I<sup>2</sup>C software reset and device ID. Interrupts can be specified by level or edge, and can be cleared individually without disturbing the other interrupt events. Also, switch debounce hardware is implemented.

This application note provides debounce circuitry operation mechanism explanations, registers setting as well as debounce circuitry measurement result.

## 2 Debounce circuitry operation mechanism

The PCAL6524 implements hardware state machine to ease the hardware interface by debouncing switch button with dedicated circuitry.

P0\_1 to P0\_7, P1\_0 to P1\_7 can connect to this debounce hardware on a pin-by-pin basis. These switch debouncers remove bounce when a switch opens or closes by requiring that sequentially clocked inputs remain in the same state for a number of sampling periods.

The output does not change until the input is stable for a programmable duration. The circuit block diagram (Figure 1) shows functional blocks consisting of an external oscillator, counter, edge detector, and D flip-flop. When the switch input state changes, the edge detector will reset the counter. When the switch input state is stable for the full qualification period, the counter clocks the flip-flop, updating the output.

The first time external clock is connected, external clock is required to wait 9 clock cycles for the debounce circuit in normal operation.

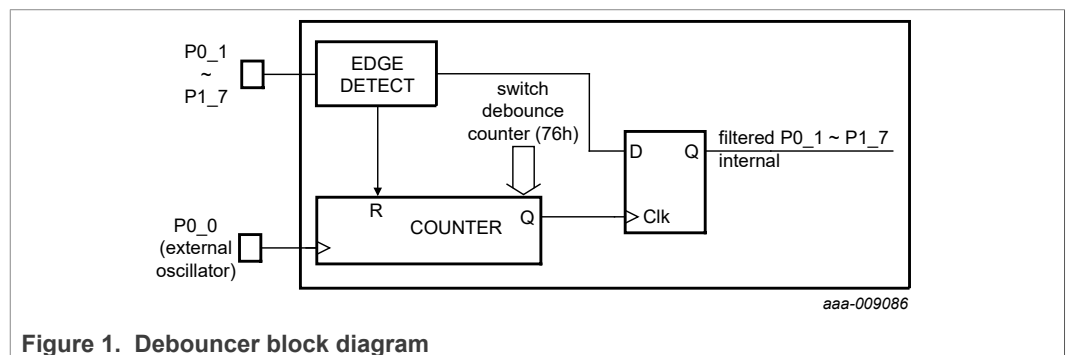


Figure 1. Debouncer block diagram

## 3 Debounce registers

There are three registers to be used for setting up debounce circuitry.

### 3.1 Switch debounce enable registers (74h, 75h)

The switch debounce enable registers enable the switch debounce function for Port 0 and Port 1 pins. If a pin on Port 0 or Port 1 is designated as an input, a logic 1 in the Switch debounce enable register will connect debounce logic to that pin. If a pin is assigned as an output (via Configuration Port 0 or Port 1 register) the debounce logic is not connected to that pin and it will function as a normal output. The switch debounce logic requires an oscillator time base input and if this function is used, P0\_0 is designated as the oscillator input. If P0\_0 is not configured as input and if SD0.0 is not set to logic 1, then switch debounce logic is not connected to any pin.

### 3.2 Switch debounce count register (76h)

The switch debounce count register is used to count the debounce time that the switch debounce logic uses to determine if a switch connected to one of the Port 0 or Port 1 pins finally stays open (logic 1) or closed (logic 0). This number, together with the oscillator frequency supplied to P0\_0, determines the debounce time.

## 4 Debounce current and function measurement

### 4.1 Test setup

The measurement was done using one OM13526 board.

1. Connect OM13515 (PCA85063A eval board) 32.768 kHz clock output to OM13526 (PCAL6524 eval board) P0\_0 port
2. Connect probe 1 to PCAL6524 P0\_0 pin
3. Connect probe 2 to PCAL6524 /INT pin
4. Connect probe 3 to PCAL6524 P1\_3 pin
5. Serial DMM to measure  $I_{DD(P)}$  current on J7
6. Serial DMM to measure  $I_{DD(I2C-bus)}$  current on J8

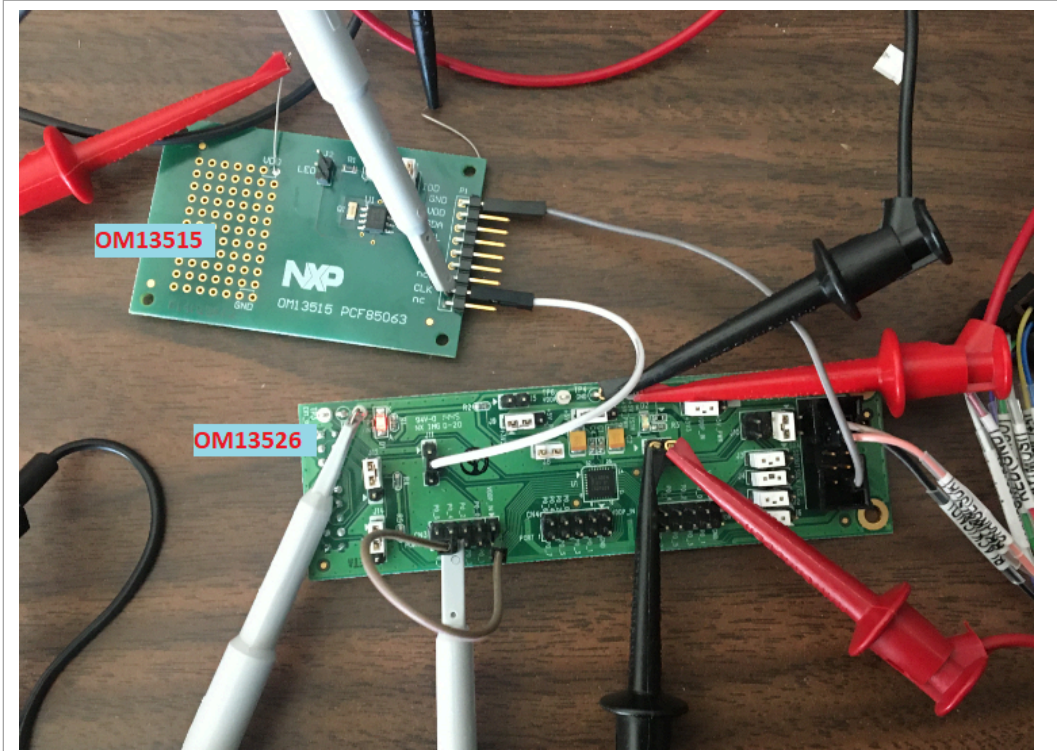


Figure 2. Test setup

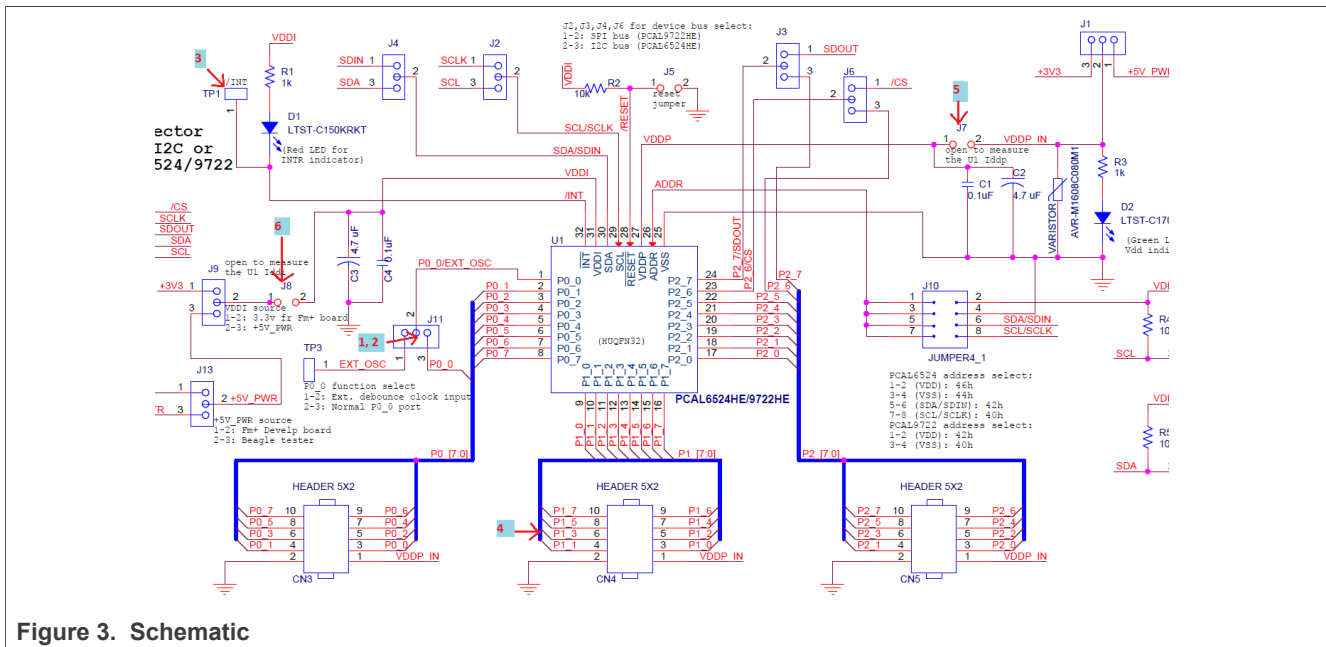


Figure 3. Schematic

### 4.2 Registers setting

- **Set switch debounce enable registers 0x74, 0x75 = 0xFF, 0xFF.**  
To enable the switch debounce function for Port 0 and Port 1 pins, P0\_0 is designated as the oscillator input port, P0\_1 – P0\_7 and P1\_0 – P1\_7 are designated as switch input port.
- **Set switch debounce count register 0x76 = 0x0A.**  
To enable the switch debounce function for Port 0 and Port 1 pins, P0\_0 is designated as the oscillator input port, P0\_1 – P0\_7 and P1\_0 – P1\_7 are designated as switch input port.

### 4.3 Current measurement data

- **$I_{DD(P)}$  and  $I_{DD(I2C-bus)}$  current measurement without 32.768 kHz clock input and without debounce function enabled:**  
– PCAL6524  $V_{DD} = 1.8\text{ V}$ , PCA85063A  $V_{DD} = 1.8\text{ V}$

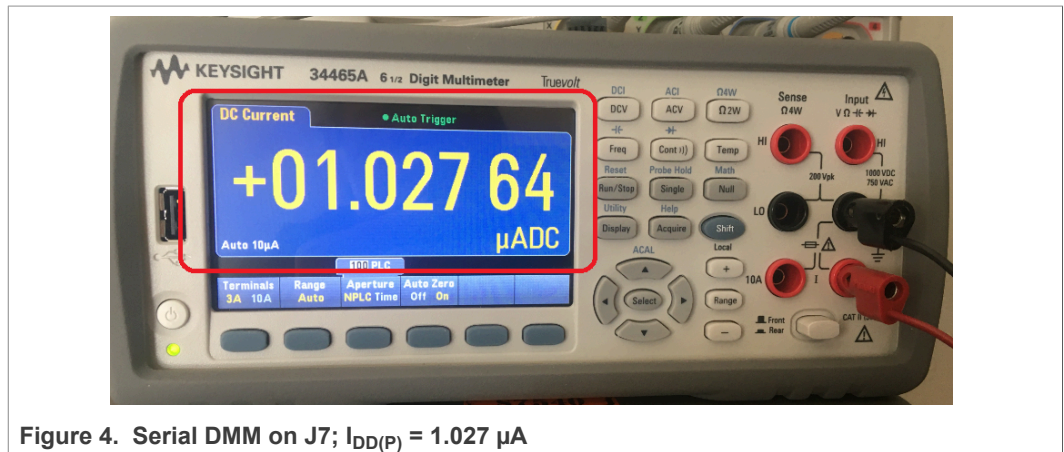


Figure 4. Serial DMM on J7;  $I_{DD(P)} = 1.027\ \mu\text{A}$

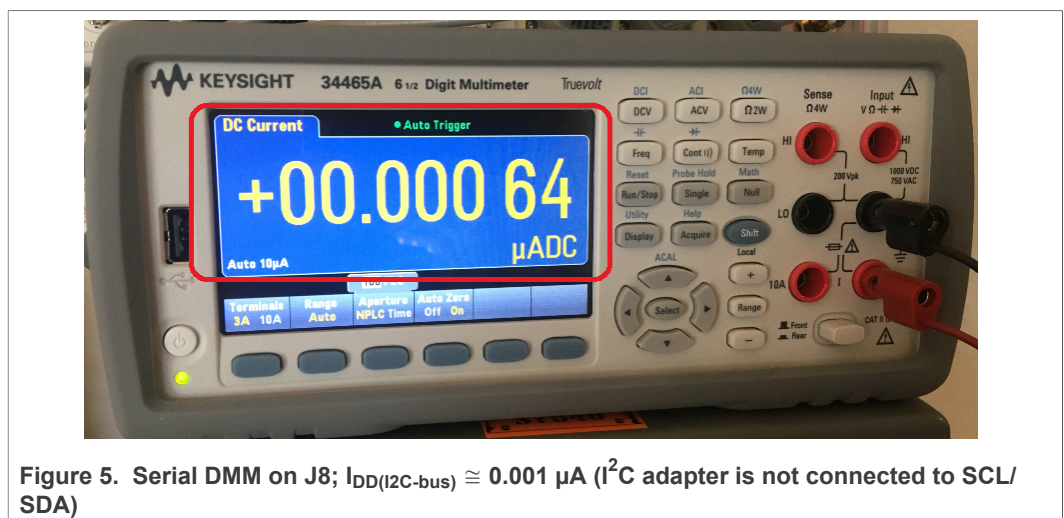


Figure 5. Serial DMM on J8;  $I_{DD(I2C-bus)} \cong 0.001\ \mu\text{A}$  (I<sup>2</sup>C adapter is not connected to SCL/SDA)

- $I_{DD(P)}$  and  $I_{DD(I2C-bus)}$  current measurement with 32.768 kHz clock input and debounce function enabled:
  - PCAL6524  $V_{DD}$  = 1.8 V, PCA85063A  $V_{DD}$  = 1.8 V
  - Write register 0x0C, 0x0D to 0xFF: Set P0-1 to be input port.
  - Write register 0x74, 0x75 to 0xFF: Set P0-1 to enable debounce function.
  - Write register 0x76 to 0x0A: Set debounce counter

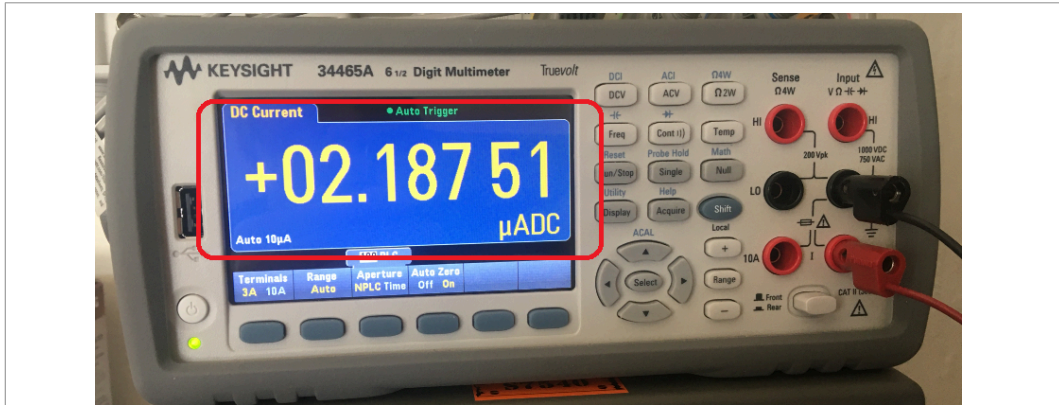


Figure 6. Serial DMM on J7; OM13515 clock output is connected to PCAL6524 P0\_0 (OM13526);  $I_{DD(P)}$  = 2.187  $\mu$ A

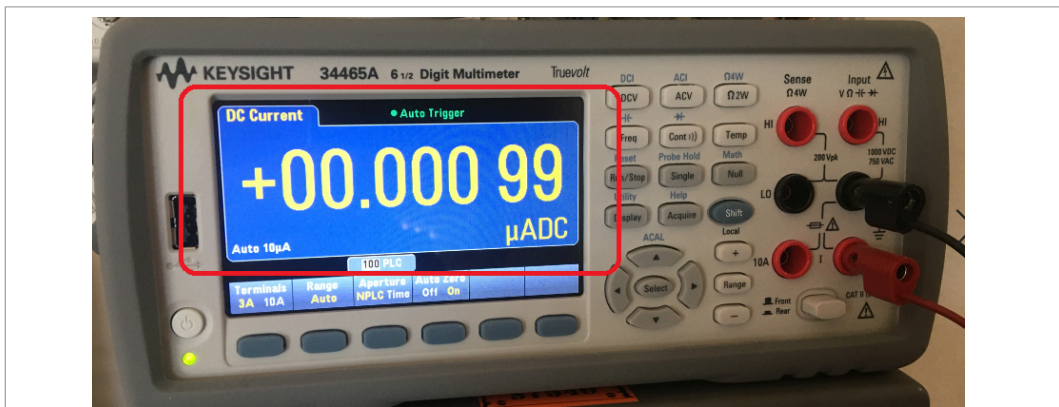


Figure 7. Serial DMM on J8;  $I_{DD(I2C-bus)}$  = 0.001  $\mu$ A ( $I^2C$  adapter is not connected to SCL/SDA)

#### 4.4 Function measurement data

- Switch goes low test:
  - Connect P1\_3 pin to low level, and capture waveform.
  - Probe 1 (Yellow) is 32KHz clock input to the P0\_0/EXT Clk pin.
  - Probe 3 (green) shows P1\_3 pin goes low level with some glitches.
  - Probe 2 (blue) shows /INT pin going low after P1\_3 level stable for 10 clock cycles.

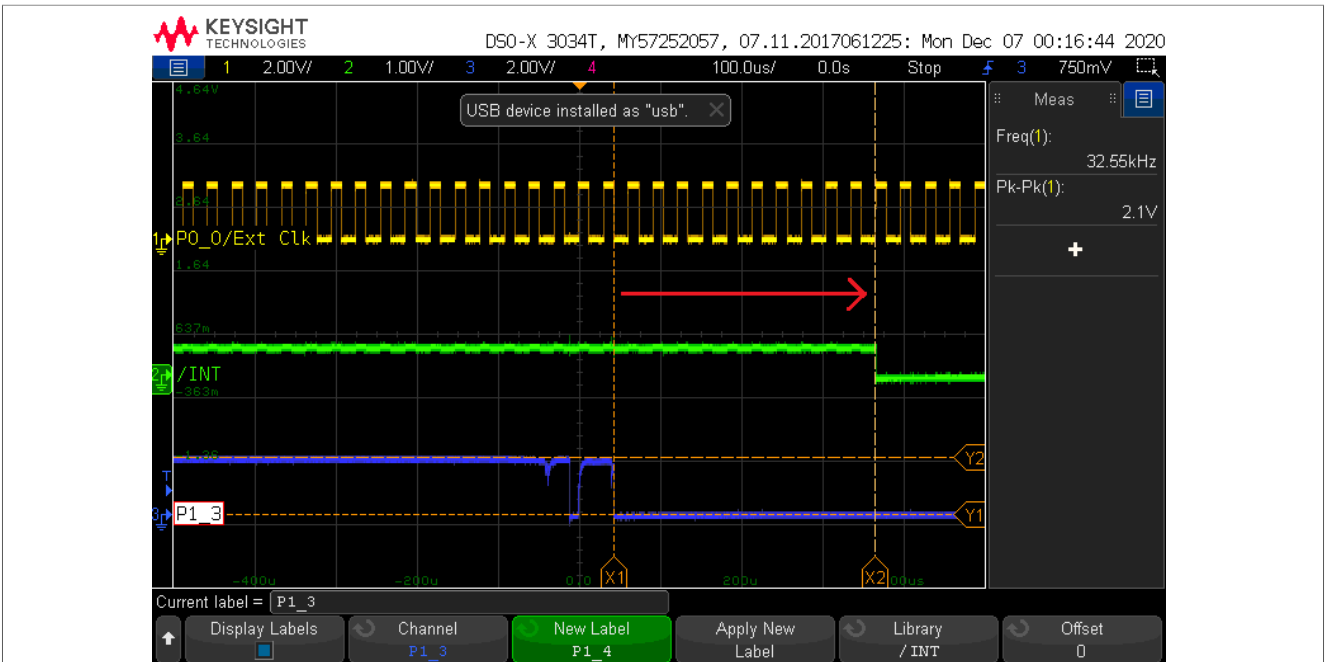


Figure 8. Switch goes low test

- Switch goes high test:
  - Connect P1\_3 pin to high level, and capture waveform.
  - Probe 1 (yellow) is 32KHz clock input to the P0\_0/EXT Clk pin.
  - Probe 3 (green) shows P1\_3 pin goes high level with some glitches.
  - Probe 2 (blue) shows /INT pin going high after P1\_3 level stable for 10 clock cycles.

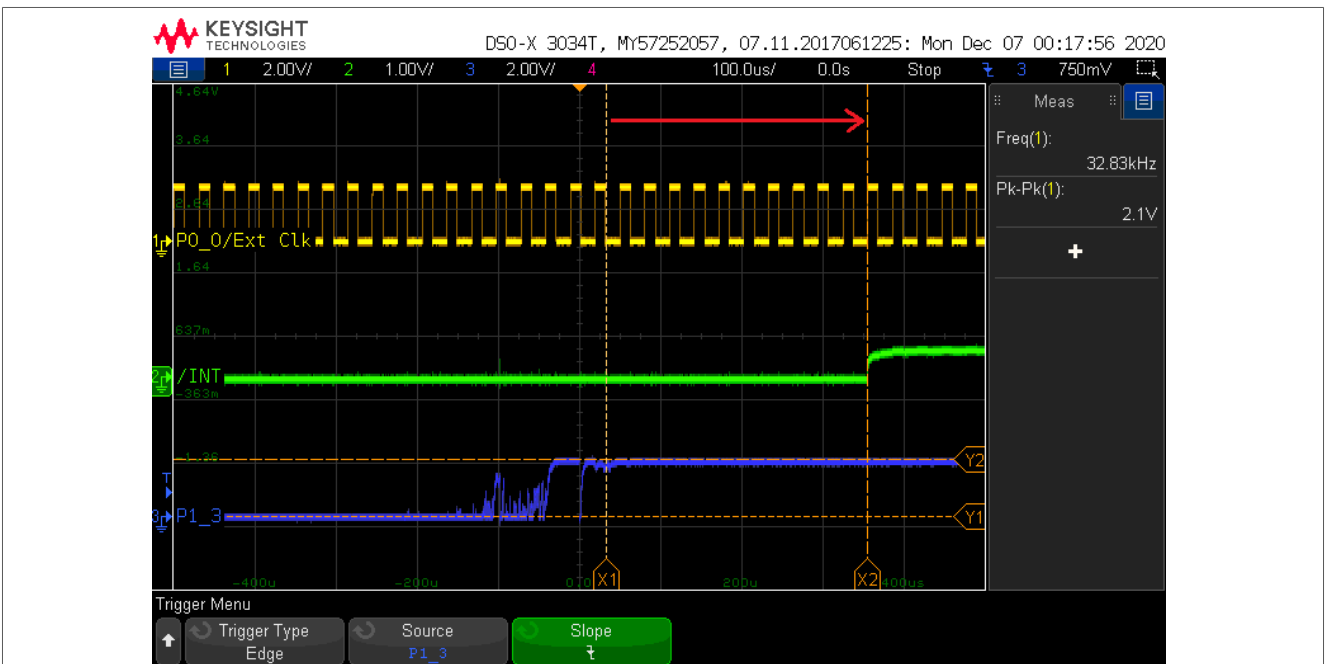


Figure 9. Switch goes high test



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